

# A Practical New Approach to 3D TCAD Simulations

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### What is TCAD?

TCAD stands for **"Technology Computer Aided Design**" where a software tool is used to simulate the semiconductor process technology and a device's electrical, thermal and optical properties

### Why TCAD?

TCAD can boost **productivity** and increase **efficiency** for semiconductor technology development in Foundries, IDMs and even fabless companies. TCAD is like **Virtual Fabrication and Testing** of semiconductors







### Why 3D TCAD?

For decades, TCAD has been limited to 2D, because:
Lack of computing power for the simulator
Device structures have little variations in the third dimension

Nowadays 3D simulation is increasingly important: •Pronounced three dimensional effect •Better understanding of device physics





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Intel's latest 22nm Ivy Bridge processor featuring 3D FINFET



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#### **GPU** simulation

Example 1: FDTD of light propagation and optical intensity Example 2: 3D circular LDMOS growth Example 3: LIGBT

#### Summary





### **3D TCAD Mesh Generation**



Prism Mesh
✓ Higher Efficiency
✓ Easier to build and control
✓ Directly extract 2D planes
✓ Better convergence

✗ Relatively new

- Tetrahedral Mesh
- ✓ Relatively mature
- ✓ Available from many vendors
- ✗ Less efficient
- ✗ Difficult to control
- X Convergent problems



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### **Example: CMOS Process Flow**





### **Example: Super Junction LDMOS**

Super Junction LDMOS can achieve lower on-resistance with the same breakdown voltage as conventional LDMOS





## **Example: Complex Interconnect**





## **Example: FINFET with NEGF**

A simple FINFET is simulated with Non-Equilibrium Green's Function (NEGF)







## Example: Simple FINFET with NEGF

- The device is divided into classical drift-diffusion (DD) region (mainly in vicinity of source/drain contacts) and quantum ballistic transport (QBT) region in the channel
- > NEGF (Non-Equilibrium Green's Function) model is employed in QBT region
- Poisson's equation solver is used in both DD and QBT regions



Electron density of val=1 sub=1 along the channel. As  $V_d$  increases, more electrons will be injected from source to drain by ballistic transport.



### **Example: Racetrack LDMOS**



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### **Bent Planes**

While straight stacking planes are good at handling rectangular shaped structures, they can be inefficient for curvatures. For arbitrary and curved structures, a novel method is to apply a new kind of planes called bent planes inserted between straight planes. These bent planes greatly optimize the mesh design in the Z direction





### **Bent Planes**

Straight planes + bent planes solution can help reduce the total mesh and avoid the unnecessarily dense mesh locations in the straight planes only method



#### With straight planes only (75) Mesh size: 33000



#### Straight planes (9) + bent planes (12) Mesh size: 4800



### **Example: Array of Silicon Pillars**



- Total Mesh Count: 52682
- Straight planes: 134
- Process Simulation time: 50 minutes

- Total Mesh Count: 4958
- Planes: 2 straight+ 16 bent planes
- Process Simulation time: 2 minutes



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### **Example: Racetrack LDMOS**



Structure with straight stacked planes only (with oxide and metal layers removed) Structure with straight and bent planes (with metal layers removed)

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#### **Example: 3D Diodes Breakdown** Stacked Stacked **Bent Planes** Net\_Doping Net\_Doping Bent Planes 20 15 15 N: 5E+15 cm-N: 5E+15 cm 10 10 N+ 5 5 Đ. N+ 0 0 +Z +Z -5 20 -5 20 15 -10+X 20 -10+X 20 10 -15 -15 -20 -20

Elec Field Mag. (V/cm) Electric field crowding 500000 450000 400000 Elec Field Mag. (V/cm) 350000 300000 300000 250000 250000 200000 150000 200000 100000 50000 0 150000 100000 20 20 15 50000 15 10 10 y(micron) 0 x(micron)

Breakdown Voltage= 50V

Elec Field Mag. (V/cm)



#### Breakdown Voltage= 67V



### **Example: Vertical DMOS and Diode**



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### **GPU Simulation**



Simplified CPU Architecture

**Simplified GPU Architecture** 

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### **GPU Simulation Benchmark**

GPU (Graphic Processing Unit) simulation enables large scale parallels simulation to greatly reduce simulation time



Process simulation benchmark test with GPU+CPU and CPU only

Intel core i7 3770 with 32 G memory and 64bit Windows 7 OS. GPU: NVidia Geforce GTX 690

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### **GPU Simulation:**

FDTD (Finite-difference time-domain) simulation of light propagation and optical intensity from top of a lens







### **Example: 3D Circular LOCOS Growth**

LOCOS: Local Oxidation of Silicon, simulated with GPU



Oxidation and diffusion are the most time consuming steps in a semiconductor process simulation. Fortunately, it is possible to make the simulation job done in parallel. GPU simulation of oxidation and diffusion greatly reduces the total simulation time

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## **Example: LIGBT Switch-off Transient**

Transient simulation of a segmented anode Lateral Insulated Gate Bipolar Transistor (LIGBT) with GPU



Hole plasma diminishing in the silicon overtime

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### **Summary**

### Practical new approaches for 3D TCAD simulation:

- Prism mesh instead of conventional pyramid mesh for less convergent issues and more efficient mesh generation
- ✓ Bent planes are created for curvatures and arbitrary shapes in the Z direction
- ✓ GPU simulation can dramatically reduce simulation time

\* CPU: i7-3770, GPU: NVidia Geforce GTX 690, Memory: 32 G

Devices	Mesh size	Process simulation time (GPU)	Device simulation time (GPU)
3D E-field	35,000	20 minutes	1.1 hours
LIGBT	167,000	2 hours	35 hours
Super Junction LDMOS	177,000	4.25 hours	55 hours





### **About Crosslight**

A Canadian company with **20** years of history The world's **first** commercial TCAD for laser diode The world's **NO.1** provider of optics and photonics TCAD The world's **most advanced** stacked planes 3D TCAD





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